SDAS210C - DECEMBER 1982 - REVISED JULY 1996

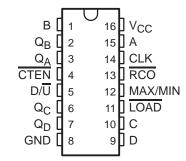
- Single Down/Up Count-Control Line
- Look-Ahead Circuitry Enhances Speed of Cascaded Counters
- Fully Synchronous in Count Modes
- Asynchronously Presettable With Load Control
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

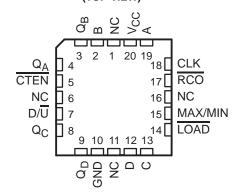
The 'ALS191A are synchronous 4-bit reversible up/down binary counters. Synchronous counting operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincidentally with each other when instructed by the steering logic. This mode of operation eliminates the output counting spikes normally associated with asynchronous (ripple-clock) counters.

The outputs of the four flip-flops are triggered on a low-to-high-level transition of the clock (CLK) input if the count enable (\overline{CTEN}) input is low. A high at \overline{CTEN} inhibits counting. The direction of the count is determined by the level of the down/up (D/ \overline{U}) input. When D/ \overline{U} is low, the counter counts up, and when D/ \overline{U} is high, the counter counts down.

SN54ALS191A . . . J PACKAGE SN74ALS191A . . . D OR N PACKAGE (TOP VIEW)



SN54ALS191A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

These counters feature a fully independent clock circuit. Changes at the control inputs ($\overline{\text{CTEN}}$ and $\overline{\text{D/U}}$) that modify the operating mode have no effect on the contents of the counter until clocking occurs. The function of the counter is dictated solely by the conditions meeting the stable setup and hold times.

These counters are fully programmable. Each output can be preset to either level by placing a low on the $\overline{\text{LOAD}}$ input and entering the desired data at the data inputs. The output changes to agree with the data inputs independently of the level of the clock input. This feature allows the counters to be used as modulo-N dividers by simply modifying the count length with the preset inputs.

CLK, D/\overline{U} , and \overline{LOAD} are buffered to lower the drive requirement, which significantly reduces the loading on (current required by) clock drivers, for long parallel words.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



SN54ALS191A, SN74ALS191A SYNCHRONOUS 4-BIT UP/DOWN BINARY COUNTERS

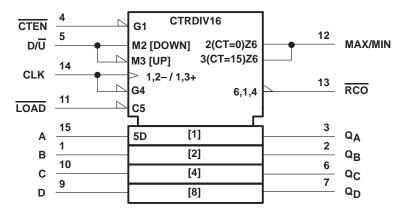
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description (continued)

Two outputs are available to perform the cascading function: ripple clock and maximum/minimum count. The latter output produces a high-level output pulse with a duration approximately equal to one complete cycle of the clock while the count is minimum (0) counting down or maximum (15) counting up. The ripple-clock output (\overline{RCO}) produces a low-level output pulse under those same conditions, but only while the clock input is low. The counter easily can be cascaded by feeding the ripple-clock output to the enable input of the succeeding counter if parallel clocking is used, or to the clock input if parallel enabling is used. The maximum/minimum count (MAX/MIN) output can be used to accomplish look ahead for high-speed operation.

The SN54ALS191A is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS191A is characterized for operation from 0° C to 70° C.

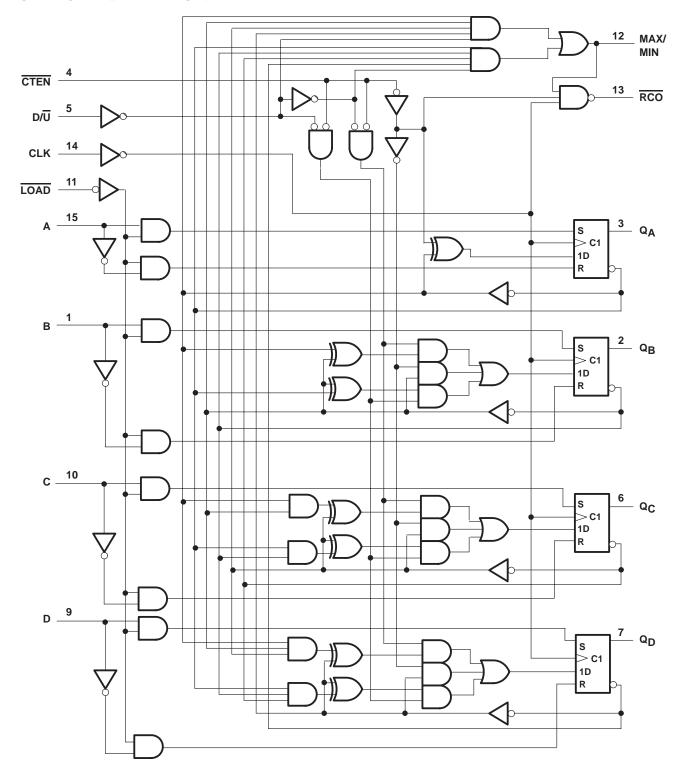
logic symbol†



 $\mbox{†}$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.



logic diagram (positive logic)



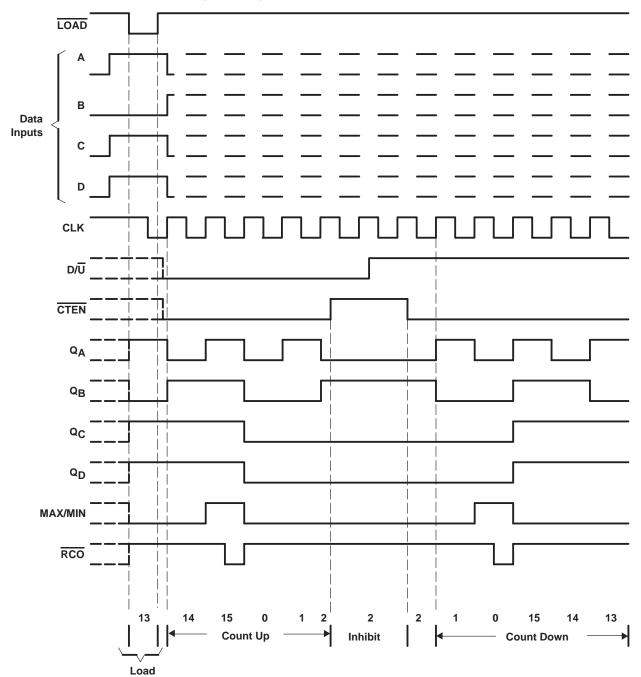
Pin numbers shown are for the D, J, and N packages.



typical load, count, and inhibit sequences

The following sequence is illustrated below:

- 1. Load (preset) to binary 13
- 2. Count up to 14, 15 (maximum), 0, 1, and 2
- 3. Inhibit
- 4. Count down to 1, 0 (minimum), 15, 14, and 13





SN54ALS191A, SN74ALS191A SYNCHRONOUS 4-BIT UP/DOWN BINARY COUNTERS

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absolute maximum ratings over operating free-air temperature range (unless oth	nerwise noted)†
Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN54ALS191A	55°C to 125°C
SN74ALS191A	0°C to 70°C
Storage temperature range, T _{stg}	. −65°C to 150°C

recommended operating conditions

			SN54ALS191A		SN74ALS191A			UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII	
Vсс	Supply voltage			5	5.5	4.5	5	5.5	V	
V_{IH}	High-level input voltage		2			2			V	
VIL	Low-level input voltage				0.7			0.8	V	
IOH	High-level output current				-0.4			-0.4	mA	
loL	Low-level output current				4			8	mA	
fclock	Clock frequency		0		20	0		30	MHz	
	Pulse duration	CLK high or low	20			16.5			20	
t _W		LOAD low	25			20			ns	
	Setup time	Data before LOAD↑	25			20				
 .		CTEN before CLK↑	45			20				
t _{su}		D/U before CLK↑	30			20			ns	
		LOAD inactive before CLK↑	20			20				
	Hold time	Data after LOAD↑	5			5				
th		CTEN after CLK↑	0			0			ns	
		D/ U after CLK↑	0		·	0				
TA	Operating free-air temperature		-55		125	0		70	°C	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN54ALS191A, **SN74ALS191A** SYNCHRONOUS 4-BIT UP/DOWN BINARY COUNTERS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54ALS191A			SN74ALS191A			UNIT	
				MIN	TYP†	MAX	MIN	TYP	MAX	UNII	
VIK		V _{CC} = 4.5 V,	$I_{I} = -18 \text{ mA}$			-1.5			-1.5	V	
Vон		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} - 2	2			
Va.		V45V	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V	
VOL		V _{CC} = 4.5 V	I _{OL} = 8 mA					0.35	0.5		
Ц		$V_{CC} = 5.5 V,$	V _I = 7 V			0.2			0.1	mA	
ΊΗ		$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μΑ	
	CTEN or CLK	V _I = 0.4 V			-0.2			-0.2	mA		
lır i	All others	V _{CC} = 5.5 V,	V = 0.4 V	-0.2		-0.1		-0.1	IIIA		
IO [‡]		$V_{CC} = 5.5 V,$	V _O = 2.25 V	-20		-112	-30		- 112	mA	
Icc		$V_{CC} = 5.5 V,$	All inputs at 0		12	22		12	22	mA	

 $[\]dagger$ All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics (see Figure 1)

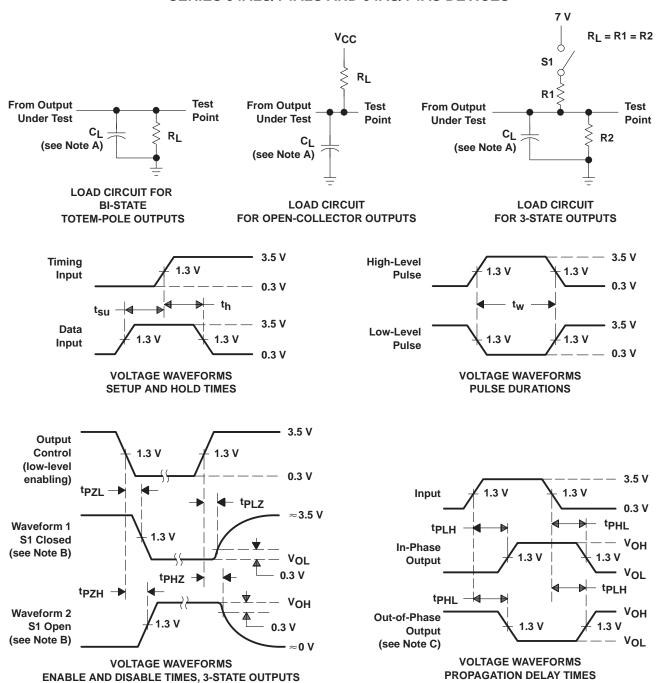
PARAMETER	FROM (OUTPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω , T_A = MIN to MAX§				UNIT
			SN54ALS191A		SN74ALS191A		
			MIN	MAX	MIN	MAX	
f _{max}			20		30		MHz
^t PLH	- IOAB	Any Q	7	37	7	30	ns
^t PHL	LOAD	Ally Q	8	34	8	30	
^t PLH		Any Q	3	25	3	21	ns
^t PHL	A, B, C, D		4	25	4	21	
^t PLH	CLK	RCO	5	24	5	20	ns
^t PHL	CLN		5	25	5	20	
^t PLH	CLK	Any Q	3	26	3	18	ns
^t PHL	OLK		3	22	3	18	
^t PLH	CLK	MAX/MIN	8	37	8	31	ns
^t PHL	CLK		8	34	8	31	
^t PLH	D/Ū	RCO	8	45	8	37	
^t PHL			10	36	10	28	ns
^t PLH	- =	BAAN/BAINI	8	35	8	25	20
^t PHL	D/Ū	MAX/MIN	8	30	8	25	ns
^t PLH	CTEN	RCO	4	21	4	18	20
^t PHL	CIEN	KOO	4	23	4	18	ns

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, los.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_{\Gamma} = t_{f} = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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